

FORM PTO-1449 (MODIFIED) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT	ATTORNEY DOCKET NO. SP01-301	SERIAL NO. To Be Assigned
APPLICANT Sabia		
FILING DATE: Herewith		GROUP: To Be Assigned

10/035564
 10/26/01
 10/035564

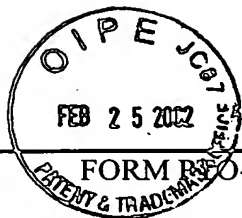
REFERENCE DESIGNATION		U.S. PATENT DOCUMENTS					
Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date if Approp.
<i>JHR</i> ↓ ✓	AA	5,915,193	6/22/99	Tong et al.	438	455	
	AB	5,785,874	7/28/98	Eda	216	24	
	AC	5,932,048	8/3/99	Furukawa et al.	156	153	
	AD	6,129,854	10/10/00	Ramsey et al.	216	18	
	AE	6,153,495	11/28/00	Kub et al.	438	459	
	AK						

FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Sub-Class	Translation Yes No
	AL						
	AM						
	AN						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)		
<i>JHR</i> ↓ ✓	AO	A. Sayah, D. Solignac, T. Cueni, "Development of novel low temperature bonding technologies for microchip chemical analysis applications," Sensors and Actuators, 84 (2000) pp. 103-108.
	AP	P. Rangsten, O. Vallin, K. Hermansson, Y. Backlund, "Quartz-to-Quartz Direct bonding," J. Electrochemical Society, V. 146, N. 3, pp. 1104-1105, 1999).
	AQ	H. Nakanishi, T. Nishimoto, M. Kani, T. Saitoh, R. Nakamura, T. Yoshida, S. Shoji, "Condition Optimization, Reliability Evaluation of SiO ₂ -SiO ₂ HF Bonding and Its Application for UV Detection Micro Flow Cell," Sensors and Actuators, V. 83, pp. 136-141, 2000.
	AR	A. Yamada, et al., Bonding Silicon wafer to Silicon Nitride With Spin-on Glass Adhesive, Electronics Letters, March 26, 1987, Vol. 23, No. 7.
	AS	D.J. Harrison, et al., Micromachining a Miniaturized Capillary Electrophoresis-Based Chemical Analysis System on a Chip, Science 261 (1993) 895-897.
	AT	W.P. Maszara, Silicon-on-insulator by Wafer Bonding: A Review, J. Electrochemical Society 138 (1991) 341-347.
	AU	D-W. Shin, et al., The Stacking Faults and Their Strain Effect at the Si/SiO ₂ Interfaces of a Directly Bonded SOI (silicon on insulator), Thin Solid Films, V. 346, pp. 169-173, 1999.
	AV	Q-Y. Tong, et al., The Role of Surface Chemistry in Bonding of Standary Silicon Wafers, J. Electrochemical Society V. 144, N. 1, pp. 384-389, 1997

EXAMINER: <i>Jenna Rossi</i>	DATE CONSIDERED: <i>7/25/03</i>
------------------------------	---------------------------------

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609: draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



COPY OF PAPERS
ORIGINALLY FILED

FORM PTO-1449 (MODIFIED)
LIST OF PATENTS AND
PUBLICATIONS
FOR APPLICANTS INFORMATION
DISCLOSURE STATEMENT

ATTORNEY DOCKET NO.

SP01-301

SERIAL NO.

10/035,564

APPLICANT Sabia et al.

FILING DATE October 26, 2001

GROUP: To Be
Assigned

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub- Class	Filing Date if Approp.
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub- Class	Translation Yes No
<i>JPL</i>	AL	52[1977]-78450	7/1/77	Japan	G02B	5/14	X
	AM						
	AN						
	AO						
	AP						
	AQ						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	
	AS	
	AT	
	AU	
	AV	
	AW	

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609: draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

FORM PTO-1449 (MODIFIED)

ATTORNEY DOCKET NO.

SERIAL NO.

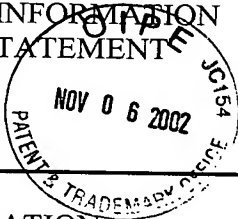
LIST OF PATENTS AND
PUBLICATIONS
FOR APPLICANTS INFORMATION
DISCLOSURE STATEMENT

SP01-301

10/06/2001

APPLICANT Sabia et al.

FILING DATE October 26, 2001

GROUP: To Be
Assigned

RECEIVED
NOV 13 2002
TC 1700

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date if Approp.
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub-Class	Translation Yes No
JLR	AL	P2000-56225A	2/25/00	Japan	G02B	27/28	X
	AM						
	AN						
	AO						
	AP						
	AQ						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	
	AS	
	AT	
	AU	
	AV	
	AW	

EXAMINER:

Jessica Rossi

DATE CONSIDERED:

7/28/03

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609: draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

SP01-301

FORM PTO-1449 (MODIFIED)

ATTORNEY DOCKET NO.

SERIAL NO.

LIST OF PATENTS AND
PUBLICATIONS

SP01-301

10/035564

FOR APPLICANTS INFORMATION
DISCLOSURE STATEMENT

APPLICANT SABIA ROBERT, et al.

FILING DATE 10/26/2001

GROUP: 2812

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Sub- Class	Filing Date if Approp.
<i>Jfl</i>	AA	5,183,710	2/2/93	Gerbino			
	AB	5,451,547	9/19/95	Himi et al			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

RECEIVED
MAR 25 2003
TC 1700

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub- Class	Translation Yes No
	AL						
	AM						
	AN						
	AO						
	AP						
	AQ						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	AR	
	AS	
	AT	
	AU	
	AV	
	AW	

EXAMINER:

DATE CONSIDERED:

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.